







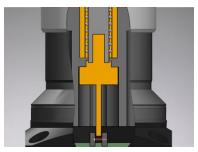
Z-Nano IR and Z-Nano RC – the wireless versions



Z-Pico - for micro-machining



Tool length measurement



The ball bearing mounted linear guide enables low measuring forces

> 0.1 mm*

> 0.2 mm**



* Depending on the geometry and material of the tool, probing force must not result in damage of tool ** With chip protection

Tool setting probe with linear working principle for monitoring the smallest tools

Tool Setting Probes Z-Series COMPACT TOOL MEASUREMENT

Robust and economic – the compact tool setting probes are extremely economic solutions for fast tool breakage detection and highly precise length measurements in machine tools. The wellproven design and the wear-free optoelectronic measuring mechanism with linear working principle, provide the highest reliability under the most adverse manufacturing conditions.

- Fast tool length measurement and breakage monitoring
- Temperature compensation

Your benefit:

- Measurement of sensitive and very small tools
- No secondary damage due to unrecognised tool breakage
- Fast ROI
- No-wear, optoelectronic measuring mechanism
- Compact and robust design

Reliable and proven transmission technologies

Tool setting probes from BLUM are available with cable, radio or infrared technology:

- Extremely fast and reliable transmission
- Sequential use of up to 6 radio measuring systems with one receiver
- Sequential use of 2 infrared measuring systems with one receiver (DUO mode)
- Simultaneous use of 2 radio measuring systems on one machine (TWIN-Mode)

System overview

Technical data

Transmission type

Minimum tool Ø

Repeatability

Height



Z-Pico

55 mm

Cable

 $1~\mu m~2\sigma$

 $0.05 \, \text{mm}^*$

Z-Nano

75 mm

Cable

0.5 μm 2σ

0,2 μm 2σ (HP) > 0.1 mm*

 $> 0.2 \, \text{mm**}$

Z-Nano IR

100 mm

Infrared

 $0.5~\mu m~2\sigma$

 $> 0.1 \text{ mm}^*$

 $> 0.2 \, \text{mm**}$